

<b>Notice of References Cited</b>	Application/Control No. 10/054,561		Applicant(s)/Patent Under Reexamination CHAN ET AL.	
	Examiner DuyVu n Deo		Art Unit 1765	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
✕	A	US-6,555,431	04-2003	Xing et al.	438/253
✕	B	US-6,432,772	08-2002	Wu et al.	438255
✕	C	US-6,399,440	06-2002	Miao	438/255
✕	D	US-6,376,326	04-2002	Lou	438/396
✕	E	US-6,218,243	04-2001	Tan et al.	438/255
✕	F	US-5,763,286	06-1998	Figura et al.	437/60
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

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	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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